

# CEI-56G – Signal Integrity to the Forefront: Testing Considerations

**Steve Sekel**  
OIF Physical & Link Layer  
Interoperability Working Group  
Chair, Keysight Technologies

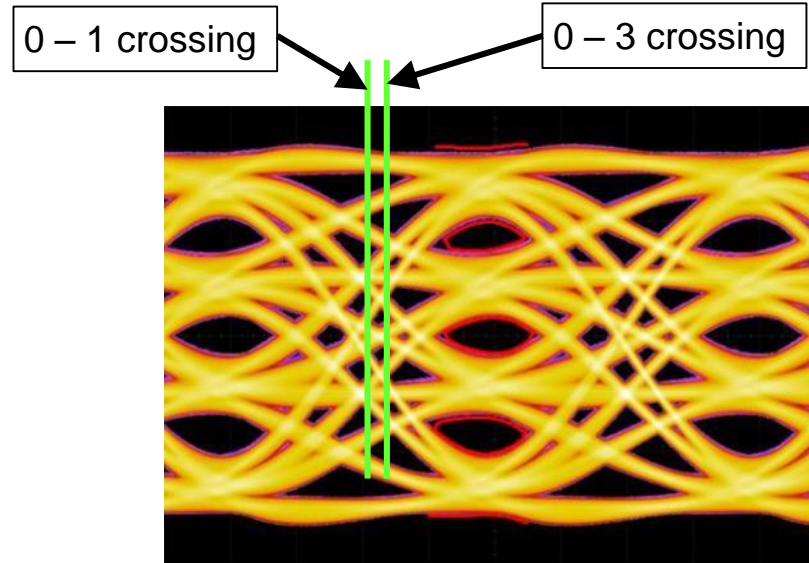
March 22, 2016



# New testing needs for 56G links

## Evolutionary versus Revolutionary

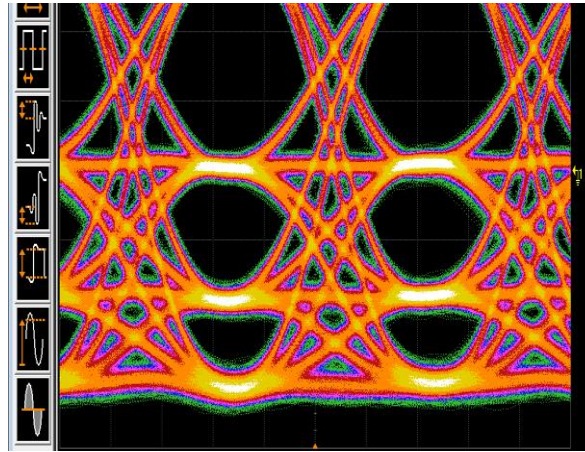
- 56G NRZ – evolutionary shift from 28G NRZ
  - Tighter jitter budgets, better loss management, totally closed eyes
- Multi-Level signaling changes all the rules – in place for 50+ years!
  - Packing 4 levels into amplitude swing of 2 – lose 9.6 dB SNR
    - Better management of noise and return loss
  - Finite rise time creates inherent DDJ
  - How to implement clock recovery?
  - Closed eyes with lower SNR
    - FEC often required



# New impairments that challenge PAM-4 receivers

It's not just timing jitter anymore!

- Non-linearity - Amplitude compression in lower eyes



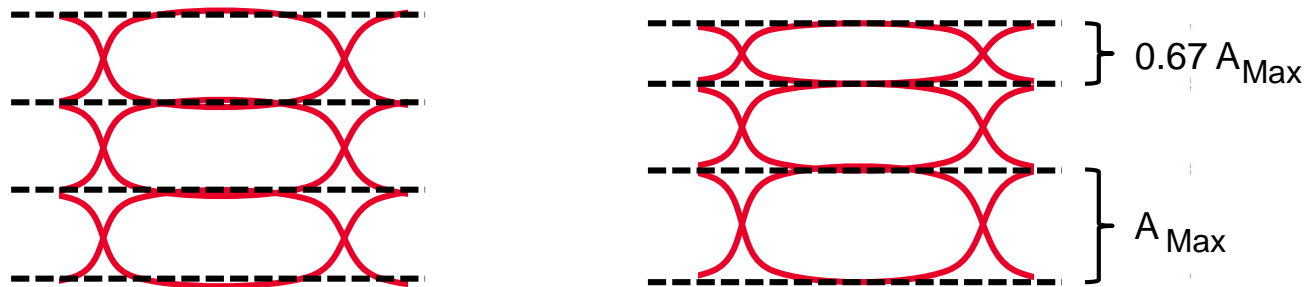
- FEC is more susceptible to burst errors than evenly distributed errors
  - Traditional BERTs do not measure burst counts

# Ensuring PAM-4 link integrity

- As PAM-4 receivers are susceptible to more than just timing jitter....
- The CEI-56G-xx-PAM Implementation Agreements are responding to assure data link integrity
- New measurements ARE being defined for Tx Outputs
- New stress tests ARE being defined for Rx Input testing

# Example: Linearity included in Input Stress Tests

- Included in CEI-56G-xx-PAM4 Implementation Agreements
- Compliance is static pass/fail test, combined with jitter or interference stress.
- Test with stressed PAM-4 eye, with inner levels offset to spec limit
- Linearity expressed as “Eye Linearity” (spec limit 0.67)
  - Set rail voltages with AWG, or individual output amplitudes with 2 channel BERT

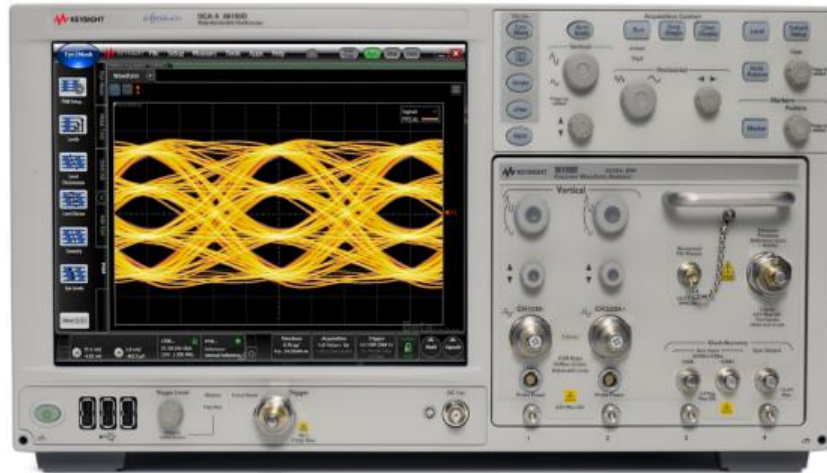


# Upgrading measurement tools for PAM-4

- A “well equipped lab” for characterizing and testing compliance of NRZ will require some new tools for PAM-4
- Good news - All IAs using PAM-4 have similar test requirements
  - Same tool set works for all

# Output (Tx) Measurement Tools

Oscilloscope remains the primary tool



- Many test instruments for Output (Tx) measurements can be upgraded from NRZ to PAM-4
  - Sampling and Real Time Oscilloscopes can add new PAM-4 measurements with optional software packages
  - Direct measurements for eye parameters, skew, linearity, noise, etc.
  - PAM-4 capable clock recovery

# Tools for Input (Rx) measurement – a different story



- Some NRZ BERTs can be upgraded to PAM-4 with added hardware
  - Analog combining or PAM – DACs
    - Use 2 NRZ channels to create single PAM-4 pattern generator channel
  - Expensive – pattern aligned channels needed to create 1 PAM-4 signal



# Native PAM-4 capable BERTs

Just starting to appear on the market



# BERT – do you need an error detector?

Many transceiver ICs have internal error counters



- High speed Arbitrary Waveform Analyzers (AWG) can generate PAM-4 directly
- Flexible to create any impairment type
- When considering, check for:
  - Adequate memory depth for long patterns
  - Ability to make changes on the fly (needed for Jitter Tolerance testing)

# Test solutions vendors

Here to help with your CEI-56G testing needs

**Amphenol**<sup>®</sup>

**Anritsu**

 **KEYSIGHT**  
TECHNOLOGIES

 **molex**<sup>®</sup>

multiLane<sub>sal</sub>

 **TE**  
connectivity

**Tektronix**<sup>®</sup>

 **YAMAICHI**  
ELECTRONICS

- Test equipment and compliance test board vendors are active members contributing to CEI-56 Implementation Agreements
- Use their application support teams to help you with your testing needs